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JD	АВ	4,157,818	06/1979	Key						
JD	AC	3,201,980	08/1965	Webb						
ന	AD	5,343,748	09/1994	Mozgowiec et al.						
ம	AE	2,573,286	10/1951	Baker, et al.						
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JD	AQ	"Microsci Journal of February	of Materials Re	d Relaxation Tests for Ultra- esearch, New York, NY, U.S.	Thin Fil ., Vol. 6	lms" - Wu T. 5, no. 2, page	W. es 407-42	<u>2</u> 6		
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